

<b>Notice of References Cited</b>	Application/Control No. 10/035,690	Applicant(s)/Patent Under Reexamination CHEN ET AL.	
	Examiner DAVID VU	Art Unit 2818	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,103,456	08-2000	Tobben et al.	430/317
*	B	US-6,042,999	03-2000	Lin et al.	430/316
*	C	US-6,251,774	06-2001	Harada et al.	438/637
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	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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